Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/827,375	LIANG ET AL.	
Examiner	Art Unit	
Paul D. Kim	3729	

	SEAR	CHED		
Class	Subclass	Date		Examiner
29	592.1 602.1 605 606 846	7/18/2006		PK
216	39, 41			
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE .	EXMR		
Reviewed Parent Application 10/200,194 (US PAT. 6,876,285)	7/18/2006	PK		
Text Search EAST/NPL (IEEE)	7/18/2006	PK		